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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
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[REDACTED] EXAMINER

MONDT, JOHANNES P

[REDACTED] ART UNIT [REDACTED] PAPER NUMBER

2826

DATE MAILED: 06/19/2003

Please find below and/or attached an Office communication concerning this application or proceeding.

Office Action Summary	Application No.	Applicant(s)	
	09/852,123	CZECH ET AL.	
	Examiner	Art Unit	
	Johannes P Mondt	2826	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133).
- Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) Responsive to communication(s) filed on 13 May 2003.
- 2a) This action is FINAL. 2b) This action is non-final.
- 3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) Claim(s) 1-12 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) Claim(s) _____ is/are allowed.
- 6) Claim(s) 1-12 is/are rejected.
- 7) Claim(s) _____ is/are objected to.
- 8) Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) The specification is objected to by the Examiner.
- 10) The drawing(s) filed on _____ is/are: a) accepted or b) objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
- 11) The proposed drawing correction filed on _____ is: a) approved b) disapproved by the Examiner.
If approved, corrected drawings are required in reply to this Office action.
- 12) The oath or declaration is objected to by the Examiner.

Priority under 35 U.S.C. §§ 119 and 120

- 13) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) All b) Some * c) None of:
1. Certified copies of the priority documents have been received.
 2. Certified copies of the priority documents have been received in Application No. _____.
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).
- * See the attached detailed Office action for a list of the certified copies not received.
- 14) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).
a) The translation of the foreign language provisional application has been received.
- 15) Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.

Attachment(s)

- | | |
|--|--|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) Paper No(s). _____ . |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152) |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449) Paper No(s) _____ . | 6) <input type="checkbox"/> Other: _____ . |

DETAILED ACTION

Continued Examination Under 37 CFR 1.114

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 05/13/03 has been entered as Paper No. 11.

Response to Amendment

Amendment B filed with RCE on 05/13/03 has been entered as Paper No. 12. In Amendment B Applicant amended claim 1 and included Remarks commented upon underneath in "Response to Arguments". Claims 1-12 are in the application.

Response to Arguments

2. Applicant's arguments filed 05/13/03 have been fully considered but they are not persuasive. In particular, Applicant traverses the rejection under 35 USC 103(a) of claim 1 on the ground that allegedly no *prima facie* case of obviousness has been establish. However, the examiner cited Wada with purpose as delineated for the inclusion of the one-track resistor (see page 4). Said purpose, namely the wider dispersion of a surge voltage is indeed obviously of relevance for any ESD protection device. Therefore, examiner is of the opinion that no further argument for its inclusion in addition to the one cited is needed and therefore the previous rejection is herewith repeated, although the wording is slightly amplified. In addition, further art substantiating the obviousness of

supplementing the device by Avery is herewith represented for the first time in the form of a patent to Ravanelli (6,147,852). Applicant's argument for his traverse of claim 2 cannot be accepted, because unlike Applicant's allegation that the invention of Smith has nothing to do with ESD devices, the mere reading of the title, "Semiconductor Device Inhibiting Parasitic Effects during Electrostatic Discharge (ESD)" reveals otherwise.

Claim Rejections - 35 USC § 103

1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

2. ***Claim 1 is rejected under 35 U.S.C. 103(a) as being unpatentable over Avery (5,043,782) in view of Wada et al (JP361292351A), or, in the alternative: in view of Ravanelli (6,147,852).*** With reference to Fig. 7: Avery teaches (cf. "Field of Invention", column 1, lines 6-9) an electrostatic discharge (ESD) protective structure that protects an integrated circuit (cf. "Summary of Invention", first line) connected between a first voltage bus 20 (cf. column 4, line 27) with a first supply voltage (inherent) and a second voltage bus or reference line 22 (cf. column 4, lines 27-28), said electrostatic discharge protective structure comprising:

a plurality of laterally designed bipolar transistors QL (cf. column 6, lines 37-42) each having a first load line connected to the first voltage bus 20 and a second line connected to the second voltage bus 22, wherein said first load lines are electrically parallel and said second load lines are electrically parallel to one another (cf. Fig. 7), each of said (laterally designed bipolar) transistors including a control connection to one of the voltage buses, namely the second voltage bus 22 (cf. Fig. 7).

Avery also teaches a resistor (RS) co-integrated into a semiconductor body preceding the control connection for one of the aforementioned laterally designed bipolar transistors QL (the one on the left in Fig. 7; cf. also column 6, lines 44-46).

Avery does not necessarily teach a single-track resistor to precede every control connection in order to enable a large input surge voltage to be more uniformly dispersed.

However, Wada et al teach the application of a one track resistor 2 co-integrated into the semiconductor body (cf. "Constitution", first sentence, in English abstract) for this very purpose in an input discharge protection circuit with parallel MIS transistors, as opposed to laterally designed bipolar transistors as in the case of Avery and Applicants (see Figure 2, Abstract, and Constitution in Wada et al). However, whether or not the transistors are lateral bipolar or MIS does not appear relevant to one of ordinary skills in the art because in both cases the purpose of a more uniform dispersal of any input surge voltage is achieved

through the same means as described in the claim. Therefore, it would have been obvious to one of ordinary skills in the art to modify the invention by Avery at the time it was made so as to include the stipulation that a single-track resistor be included as stipulated in claim 1 of Applicants.

In the alternative Ravanelli, in a patent on a ESD protection device (hence clearly analogous art; see title), teaches the inclusion of a one track resistor as Prior Art, said track resistor being co-integrated into a semiconductor body so as to precede every control connexion of a plurality of laterally designed bipolar transistors: see Figure 1 and col. 1, lines 38-45). Please note that resistor R in Figure 1 is connected to both control connexions B.

Motivation to include the teaching by Ravanelli in the invention by Avery stems from the ubiquitous advantage of "limiting the currents caused by ESDs" (Ravanelli's objective; cf. col. 1, line 45) for any ESD device including Avery's (cf. col. 1, lines 15-19), because that is what ESD protection devices are supposed to do. *Combination* of the teaching by Ravanelli and the invention by Avery is straightforward by building in the substrate according to claim 5 of Avery a resistive region (cf. col. 8, lines 4-14), which is only needed to the extent the substrate (or P-well) has an inappropriate value for the resistivity to start with. Standard methods are available for creating resistive regions in substrates. Success in implementing the said combination can therefore be reasonably expected.

In summary, claim 1 is unpatentable over Avery in view of Wada et al, and, in the alternative, claim 1 is unpatentable over Avery in view of Ravanelli.

3. **Claims 2-5 are rejected** under 35 U.S.C. 103(a) as being unpatentable over Avery and Wada et al as applied to claim 1 above, and further in view of Smith (6,075,271).

With regard to claim 2: As detailed above, claim 1 (on which claim 2 depends) is unpatentable over Avery in view of Wada et al. Avery also teaches the electrostatic discharge protective structure of claim 1 wherein the semiconductor body has embedded therein at least one emitter zone and at least one collector zone (42 and 44 in Fig. 4, respectively) of first conductivity type, and at least one base zone of second conductivity type (58 in Fig. 4).

Neither Avery nor Wada et al necessarily teach a well-shaped region inserted into said semiconductor body between said zones of the first conductivity types and said base zone or zones so as to extend the path length charge carriers have to travel to the base zone.

However, the use of a deeper doped region or well to significantly increase the path length that avalanche generated charge carriers have to travel as a means to increase the collector-to-emitter voltage in bipolar transistor dynamics is a method well-known in the art, as witnessed by Smith, who teaches a deeper doped region or well-shaped region 80 (cf. abstract, lines 12-17, and Fig. 7) acting as a barrier for the avalanche-generated charge carriers involved in bipolar snap-back by blocking said

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charge carriers laterally, increasing the path length to be traversed by them, whereby a higher percentage of them reach the substrate 65 instead and are thus shunted to ground. Because of the specifically stipulated *motivation* as given above and the field of application, namely: technology to increase the bipolar snapback problem, it would have been obvious to one of ordinary skills in the art to modify the invention as essentially taught by Avery and Wada et al so as to include the further limitation of claim 2.

With regard to claims 3-5: the deeper doped region as taught by Smith is connected to zone 110 of first conductivity type (cf. column 4, lines 30-31 and column 7, lines 10-12) (*claim 3*) which is an electrode or source zone (cf. column 7, lines 8-9), while the examiner takes official notice that electrode or source zones intrinsically have a higher doping concentration than the other regions within the substrate (*claim 4*). The well-shaped region 80 extends more deeply into the substrate than said zone 110 to which it is attached (cf. Fig. 7).

4. ***Claim 6 is rejected*** under 35 U.S.C. 103(a) as being unpatentable over Avery, Wada et al, and Smith as applied to claim 5 above, and further in view of Li et al (5,623,387). As detailed above, claim 5 (on which claim 6 depends) is unpatentable over Avery and Wada et al as applied to claim 1, in further view of Smith. Neither Avery, nor Wada et al, nor Smith necessarily teach the further limitation of claim 6. However, the lateral enclosure of transistors by doped zones connected through metal contacts is well known in the art as an obvious way (creation of equipotential lines through enclosure by conductors) of creating favorable conditions for a more uniform conduction

of current between emitter and collector zones in transistors, as witnessed by Li et al, who teach an esd protection circuit (cf. title) involving a bipolar transistor (cf. abstract), specifically the surrounding of first conductivity type emitter and collector zones 431, 435, by second conductivity type zones 422 connected to a common metal contact 423 (cf. Fig. 6B; see also Fig. 7B) (cf. column 13, lines 54-59). Therefore, it would have been obvious to one of ordinary skills in the art to modify the invention of claim 5 so as to include the further limitation of claim 6.

5. ***Claims 7- 12 are rejected under 35 U.S.C. 103(a) as being unpatentable over Avery, Wada et al, Smith, and Li et al as applied to claim 6 above, and further in view of Wong et al (6,277,689).*** As detailed above, claim 6 (on which claim 7 depends) is unpatentable over Avery, Wada et al, and Smith, in further view of Li et al.

Avery, Wada et al, Smith, nor Li et al, necessarily teach the further limitation defined by claim 7, except for the presence of charge carriers of the first conductivity type (see Smith, column 1, lines 37-43).

However, the use of embedded wells for the purpose of combating volatility in lateral bipolar transistors is well known in the art as witnessed by Wong who teaches a P-well 34 embedded in an N-well 36 within a substrate 38 (cf. Fig. 4 and column 3, lines 60-64).

Therefore, it would have been obvious to one of ordinary skills in the art to modify the invention as defined by claim 6 at the time at the time of the invention so as to include the further limitation of claim 7.

With regard to claim 8: emitter and collector zones 42 and 44, respectively, as shown in Fig. 4 of Avery are designed as strips and are disposed alternately next to one another and parallel to one another. Thus the further limitation of claim 8 does not distinguish over the prior art.

With regard to claim 9: Figure 6 in Avery shows that the electrostatic discharge structure of Avery configured and arranged in an essentially square layout. Thus the further limitation of claim 9 does not distinguish over the prior art.

With regard to claim 10: the examiner takes official notice that the provision of thorough contacts between electrodes and emitter/collector regions is an obvious requirement for any transistor; without it the current through the device would be impeded and the voltage between emitter and collector would be compromised.

Therefore, the further limitation of claim 10 does not distinguish over the prior art.

With regard to claim 11: The electrostatic discharge structure taught by Wada et al comprises emitter and collector electrodes connected via conductor tracks (inherent property of electrodes in any working electronics device of which they form a part) to oppositely situated voltage buses (cf. Fig. 2) and form finger-like connections (four fingers on each side in Fig. 2) which are staggered with one another so as to render as much electrostatic balance to the configuration as possible, as indicated by the locations L1, L2, L3, and L4 in Fig. 1 in Wada et al.

With regard to claim 12: the bipolar transistor electrostatic discharge structure as taught by Avery is designed as a field oxide bipolar transistor structure, as shown by Fig. 5.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Johannes P Mondt whose telephone number is 703-306-0531. The examiner can normally be reached on 8:00 - 18:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Nathan J Flynn can be reached on 703-308-6601. The fax phone numbers for the organization where this application or proceeding is assigned are 703-308-7722 for regular communications and 703-308-7724 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

JPM
June 8, 2003

Minhloan Tran
Minhloan Tran
Primary Examiner
Art Unit 2826